

MACRO-SCALE CONTACTLESS CHARACTERISATION OF GRAPHENE-BASED TRANSPARENT ELECTRODES

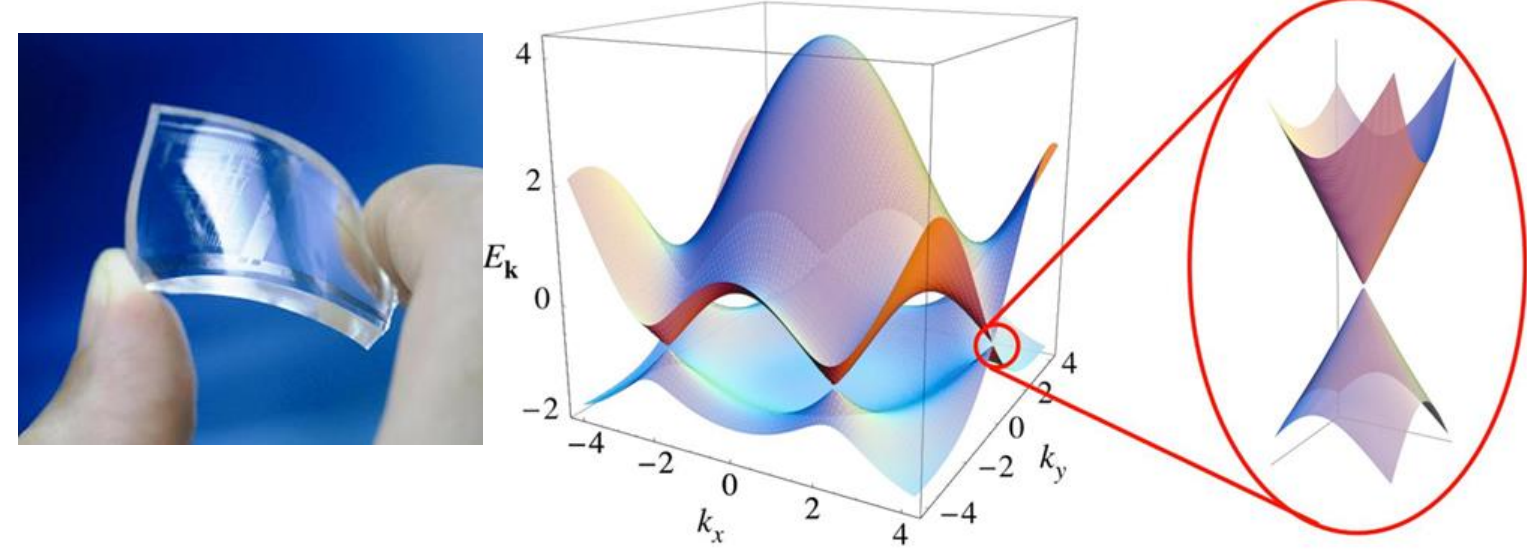
S. Fernández, J.J. Gandía, A. Inés, I. Arnedo, M. de la Cruz, A. Bosca, J. Pedrós, M.A. Pampillón, A. Molinero, M.B. Gómez-Mancebo, F. Calle, J. Cárabe, J. Martínez, I. Rucandio



Motivation & Objectives

Why use Graphene? Unique properties^[1]:

- Flexibility
- Conductivity
- Transparency
- Mechanical resistance
- No energy gap
- Environmental stability



Possible technological application

Graphene in Photovoltaic sector^[2]: Which technology to be used?

- Low temperature reliable solution: Silicon-heterojunction (SHJ) technology:
 - Promising approach
 - To extract the current more efficiently (Not losing optical performance)
 - Main bottleneck to reach the industrial production scenario:
 - Quality production control at large areas

Objective: Efficient macro-scale + non-destructive contactless mapping methods

- To evaluate key Graphene performance indicators
- To determine Graphene suitability, depending on the field application
- To determine the uniformity + quality Graphene-transfer process

Desired properties to be used as Transparent Electrode (TE)

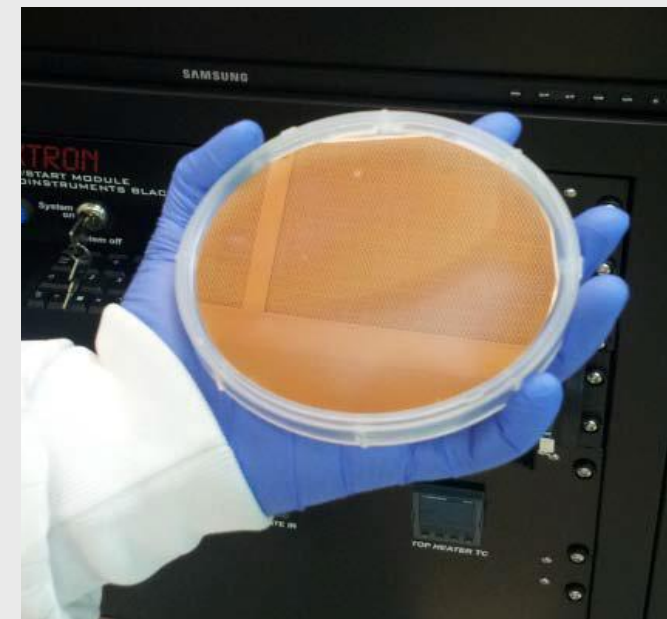
GRAPHENE SYNTHESIS AND TRANSFER

Aixtron BM Pro Chemical vapor deposition (CVD)

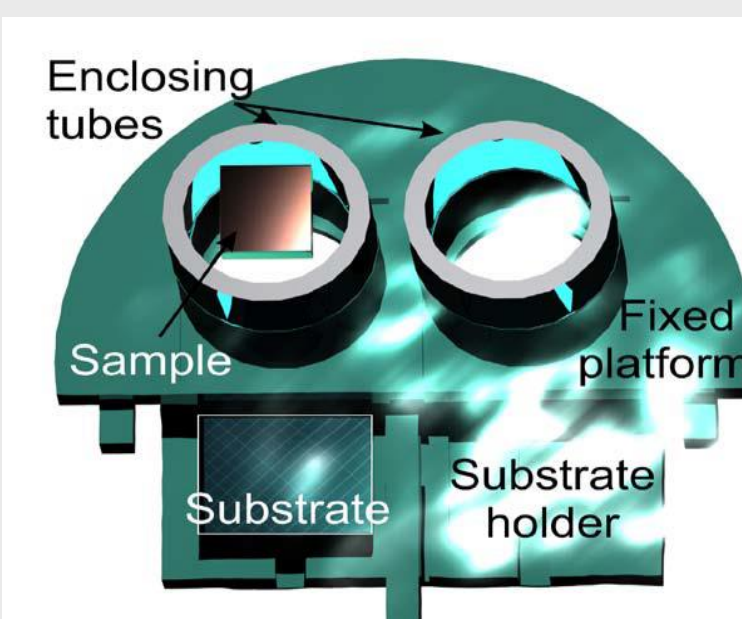


Fabrication steps:

- Heating: Ar
- Deposition: H₂ + Ar + CH₄
- Cooling



- 4-inch substrates: Cu foil or Cu/SiO₂/Si(111) wafers
- Single layer graphene, defect free

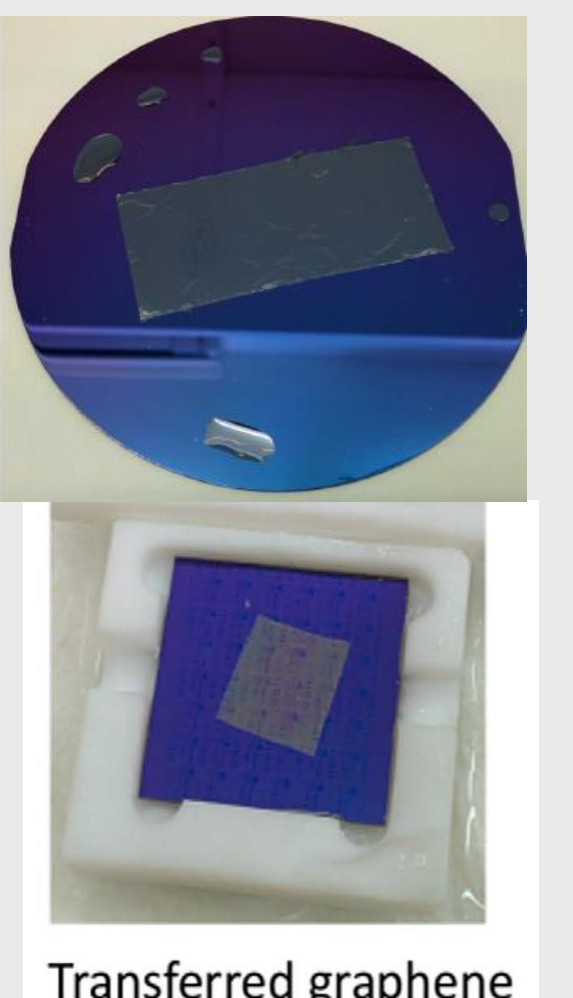


Automatic system ensures:

- Self-centering system
- Liquid flow control
- Arbitrary substrate types
- Reproducibility
- Scalability to technological route

Patent ES 2 536 491 B2; W02015/075292 A1^[3]

Single layer graphene, with improved electrical performance



CHARACTERISATION OF GRAPHENE-BASED TRANSPARENT CONDUCTIVE ELECTRODES: Meso-scale contactless mapping methods

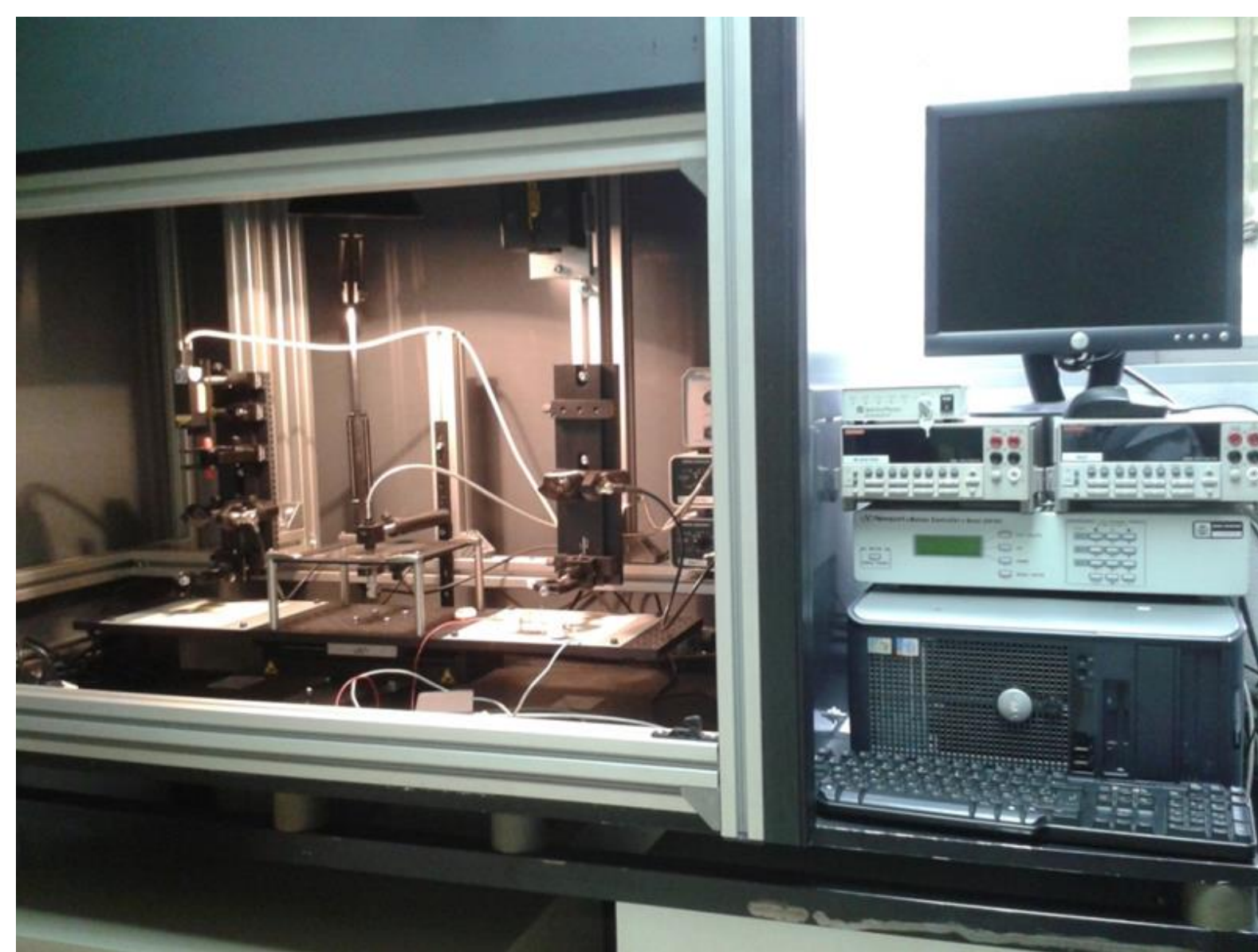
Graphene monolayers
80 nm- TCO
Substrate

Analysed TCE structure

- TCE Structure: (i) Graphene monolayers (GML): 3 + (ii) TCO: 80-nm thick ITO film^[3]
- Substrates: Corning glass and Silicon
- Application field: Front-electrode for SHJ solar cell technology

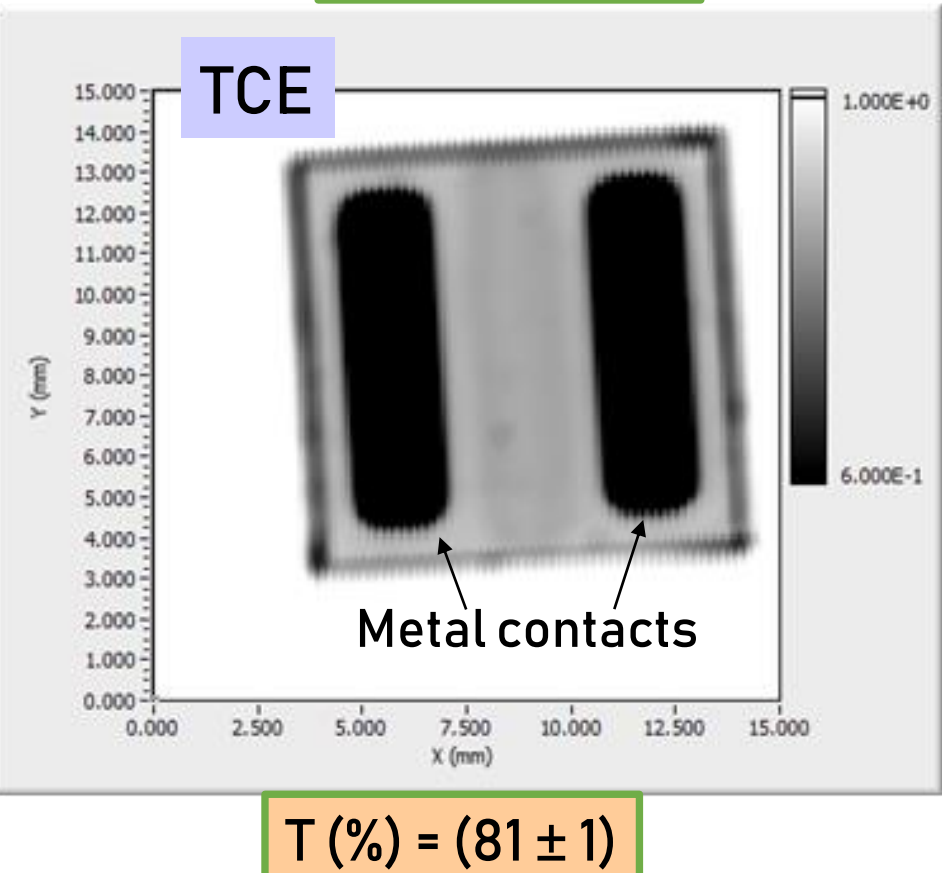
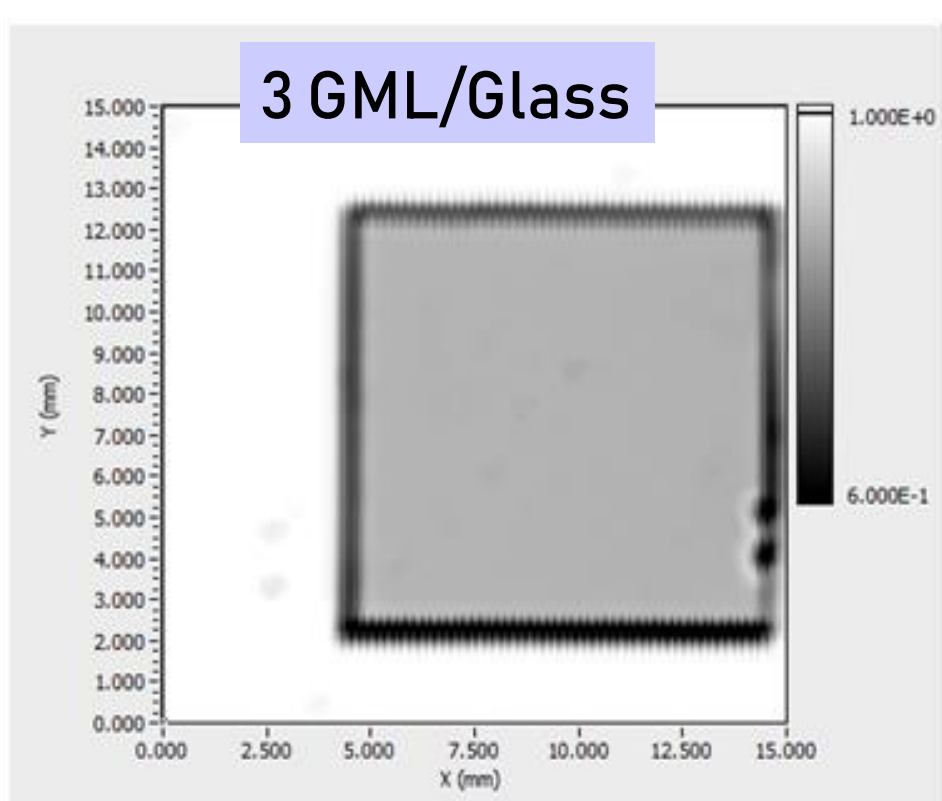
Optical transmission mapping home-made system:

- Focused white-light lamp
- X-Y positioner set
- Current preamplifiers
- Reference photodiode
- Digital voltmeters



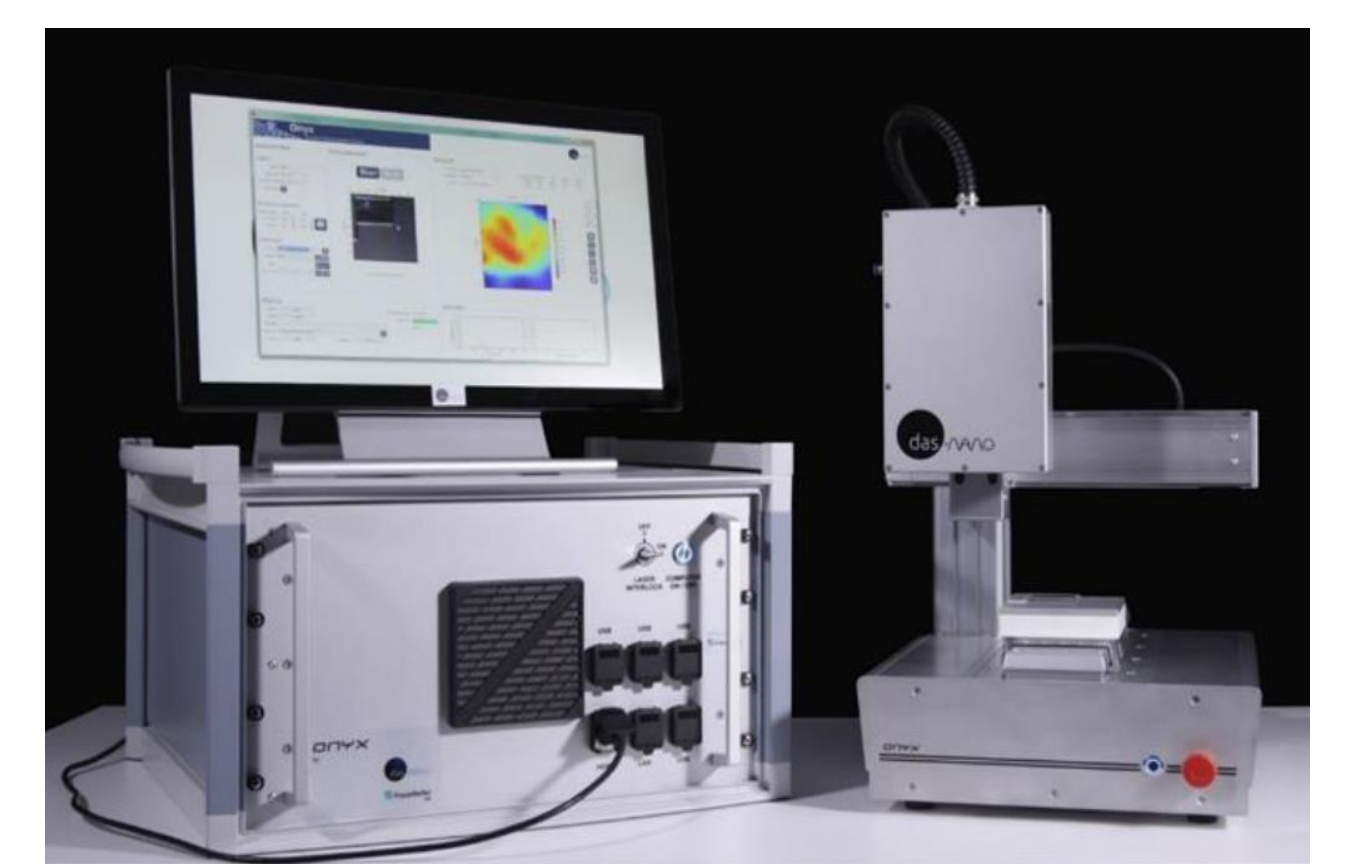
- At room temperature
- No need sample preparation
- Large areas analysed

- Good homogeneity in optical maps:
 - High reproducibility of transfer-method
- Transmittance, close to theoretical value:
 - High quality of Graphene material



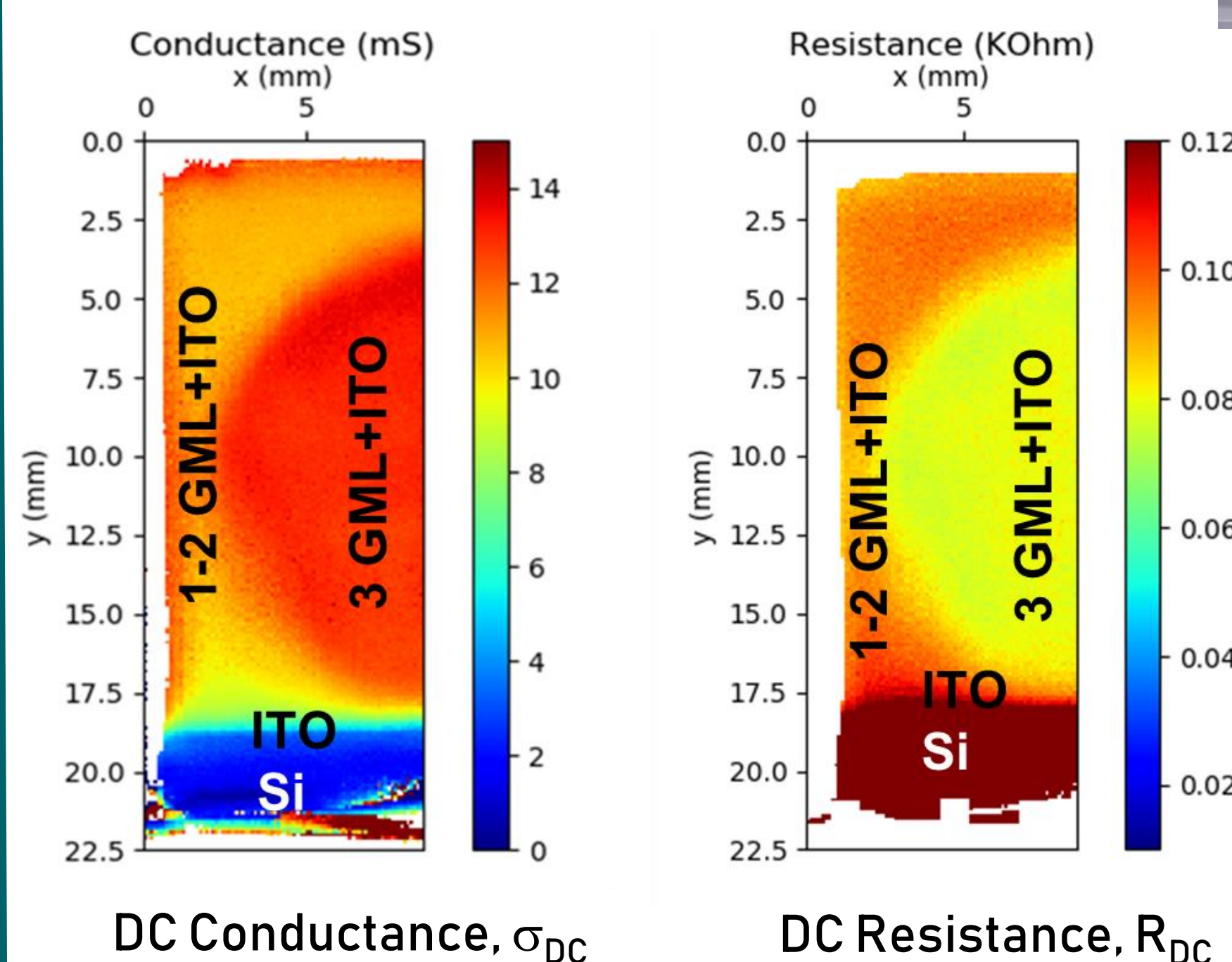
ONYX SYSTEM from Company^[*]: das-Nano

- THz time-domain spectrometer
- Contactless and non-destructive
- Industrial quality control tool
- High speed analysis of large areas
- Reflection mode operability
- No need for sample preparation
- Room temperature measurements



[*] <https://www.das-nano.com/>

[*] Azanza, E. et al., S.L. Quality inspection of Thin films materials. US Patent, US 10,267,836 (B2), 2019 April 23: das-Nano



- High sensitivity to small variations ⇒ Goodness of transfer-method
- Determination of electrical parameters ⇒ Key Graphene indicators + Suitability of Graphene-based structures

CONCLUSIONS

Use of these approaches allows opening new horizons to achieve the definitive take off of Graphene-based technologies.

CONTACT PERSON

Susana M^a Fernández,
CIEMAT, Avda. Complutense 40,
Madrid 28040, Spain.
E-mail:
susanamaria.Fernandez@ciemat.es
Tlf: +34 3466039

REFERENCES

- K.S. Novoselov et al., Science 306 (2004) 666.
- M.A. Green et al., Prog. Photovoltaic: Res. Appl. 24 (2016) 905.
- S. Fernández et al., Micromachines 10 (2019) 402.
- A. Bosca et al., Sci. Rep. 6 (2016) 21676.

Partial financial support was provided by Ministry of Economy and Competitiveness under DIGRAFEN (ENE2017-88065-C2-1-R) and (ENE2017-88065-C2-2-R). The authors acknowledge to the project of Community of Madrid NMT2D-CM (S2018/NMT-4511).